

Aromatic hydrocarbons, $C_6 - C_8$

Analysis of impurities in p-xylene

Application Note

Materials Testing & Research

Authors

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Introduction

Gas chromatography with an Agilent CP-Wax 52 CB column detects five impurities in p-xylene in 20 minutes.



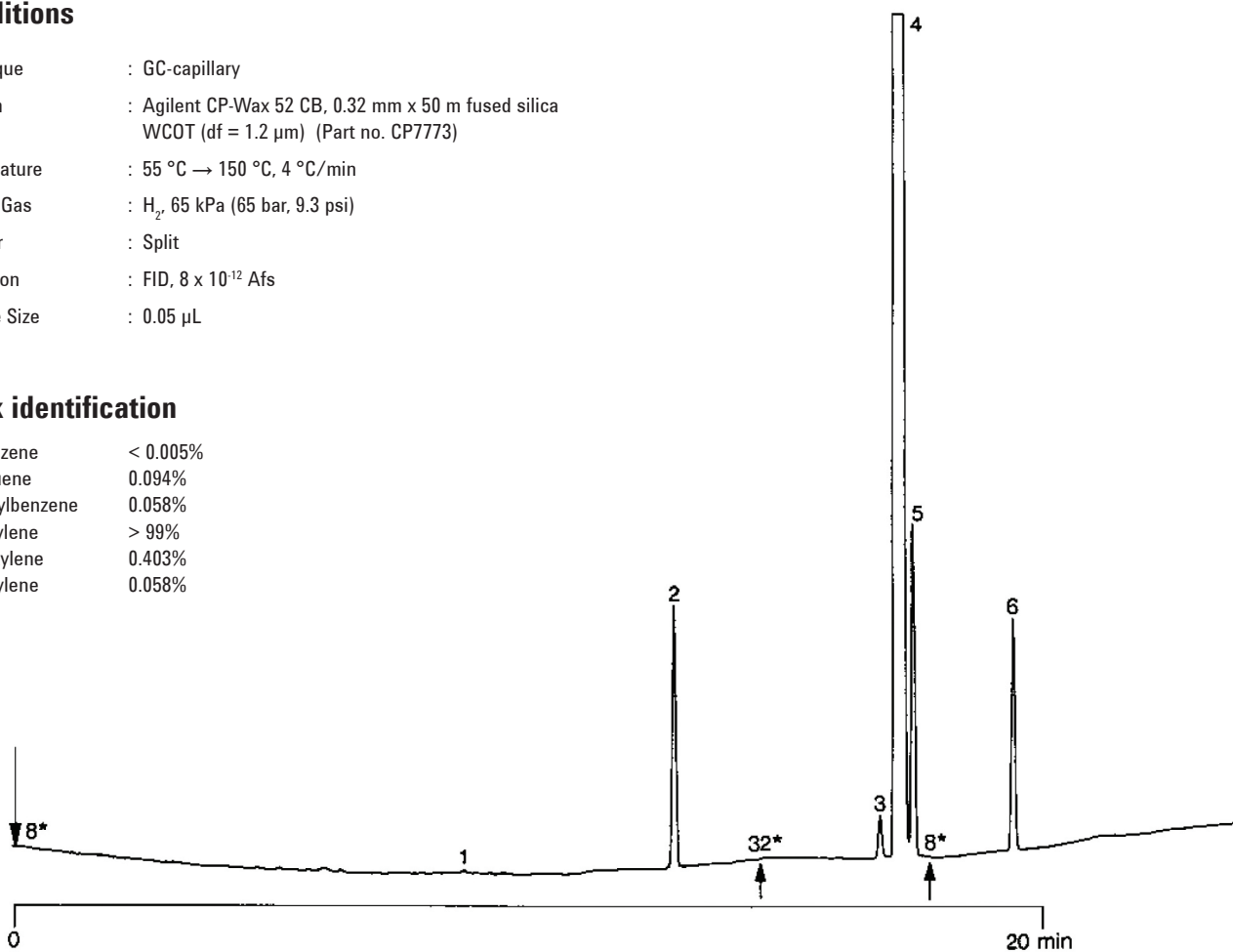
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Conditions

Technique : GC-capillary
Column : Agilent CP-Wax 52 CB, 0.32 mm x 50 m fused silica
WCOT (df = 1.2 μ m) (Part no. CP7773)
Temperature : 55 °C \rightarrow 150 °C, 4 °C/min
Carrier Gas : H₂, 65 kPa (65 bar, 9.3 psi)
Injector : Split
Detection : FID, 8 x 10⁻¹² Afs
Sample Size : 0.05 μ L

Peak identification

1. benzene	< 0.005%
2. toluene	0.094%
3. ethylbenzene	0.058%
4. p-xylene	> 99%
5. m-xylene	0.403%
6. o-xylene	0.058%



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